Topical Collection

Optical Design and Engineering

Message from the Collection Editors

This is a feature issue to present recent advances and future prospects of this key, fundamental, research area in (1) optical design and engineering of semiconductor device, (2) optical measuring equipment and (3) optical exposure equipment. You are cordially invited to submit your original research or review papers to this Special Issue. Potential topics include, but are not limited to:

- Optical materials;
- Non-imaging optical design;
- Imaging optical design;
- Optical lens design;
- Solid state lighting;
- Thin-film technology;
- Optical instruments;
- Opto-mechanical system;
- Optical exposure equipment;
- Imaging systems, image processing, and display optical systems;
- Optical devices, photonic devices, sensors, and detectors.

Dr. Zhi Ting Ye

Collection Editors

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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